TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π -MOS V)

2SK3176

Switching Regulator, DC-DC Converter and Motor Drive Applications

• Low drain-source ON resistance: $RDS(ON) = 38 \text{ m}\Omega \text{ (typ.)}$

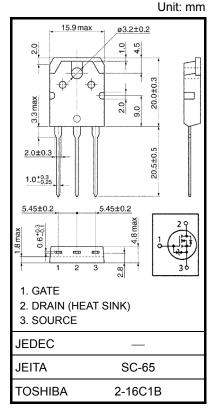
• High forward transfer admittance: $|Y_{fs}| = 30 S$ (typ.)

• Low leakage current: $IDSS = 100 \mu A \text{ (max) (V}_{DS} = 200 \text{ V)}$

• Enhancement-mode: $V_{th} = 1.5 \text{ to } 3.5 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA)}$

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Symbol Rating		
Drain-source voltage		V_{DSS}	200	V	
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)		V_{DGR}	200	V	
Gate-source voltage		V_{GSS}	±20	V	
Drain current	DC (Note 1)	I _D	30	Α	
	Pulse (Note 1)	I_{DP}	120	A	
Drain power dissipation	$(Tc = 25^{\circ}C)$	P_{D}	150	W	
Single pulse avalanche energy (Note 2)		E _{AS}	925	mJ	
Avalanche current		I _{AR}	30	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	15	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55 to 150	°C	



Weight: 4.6 g (typ.)

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: $V_{DD} = 50$ V, $T_{ch} = 25$ °C (initial), L = 1.66 mH, $R_G = 25$ Ω , $I_{AR} = 30$ A

Note 3: Repetitive rating: pulse width limited by maximum junction temperature.

Note 4: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic sensitive device.

Please handle with caution.

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	0.833	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	50.0	°C/W

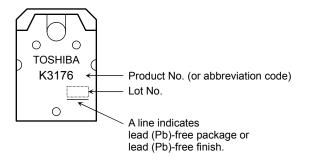
Electrical Characteristics (Ta = 25°C)

Characteri	stics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Drain cut-off current		I _{DSS}	V _{DS} = 200 V, V _{GS} = 0 V		_	100	μА
Drain-source breakdo	wn voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	200	_		V
Gate threshold voltage	9	V _{th}	V _{DS} = 10 V, I _D = 1 mA	1.5	_	3.5	V
Drain-source ON resis	stance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 15 A	_	38	52	mΩ
Forward transfer admi	ttance	Y _{fs}	V _{DS} = 10 V, I _D = 15 A	15	30	_	S
Input capacitance		C _{iss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	5400	_	pF
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	580	_	pF
Output capacitance		Coss	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	1900	_	pF
Switching time	Rise time	t _r	VGS 0 V	_	15	-	
	Turn-on time	t _{on}		_	55		ns
	Fall time	t _f			25		115
	Turn-off time	t _{off}	$V_{DD} \simeq 100 \text{ V}$ Duty $\leq 1\%$, $t_W = 10 \mu\text{s}$		190		
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq$ 160 V, $V_{GS} =$ 10 V, $I_D =$ 30 A	_	125	_	nC
Gate-source charge		Q _{gs}	$V_{DD} \simeq 160 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$	_	80	_	nC
Gate-drain ("miller") charge		Q _{gd}	$V_{DD} \simeq 160 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$		45	_	nC

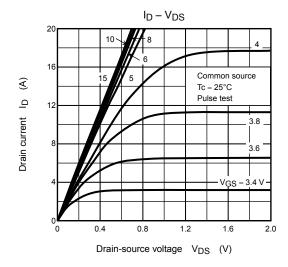
Source-Drain Ratings and Characteristics (Ta = 25°C)

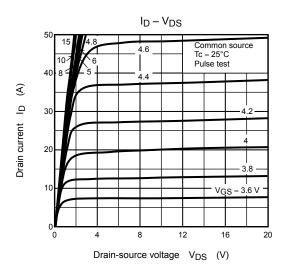
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	30	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	90	Α
Forward voltage (diode)	V _{DSF}	$I_{DR} = 30 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-2.0	V
Reverse recovery time	t _{rr}	$I_{DR} = 30 \text{ A}, V_{GS} = 0 \text{ V}, \\ dI_{DR}/dt = 100 \text{ A}/\mu \text{s}$	_	270	_	ns
Reverse recovery charge	Q _{rr}	$I_{DR} = 30$ A, $V_{GS} = 0$ V, $dI_{DR}/dt = 100$ A/ μ s		3.0	_	μС

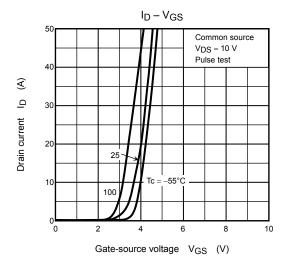
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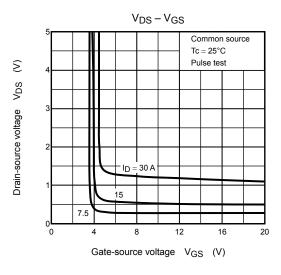


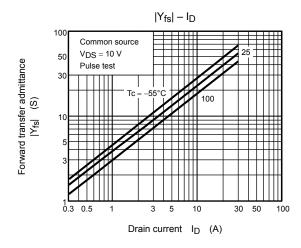
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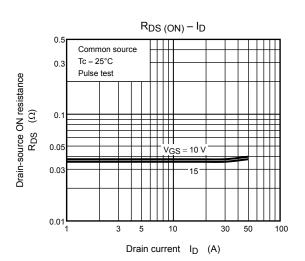




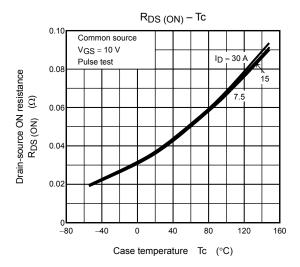


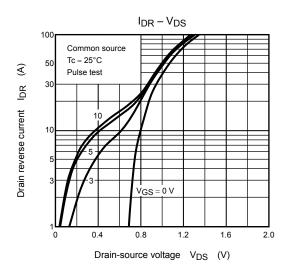


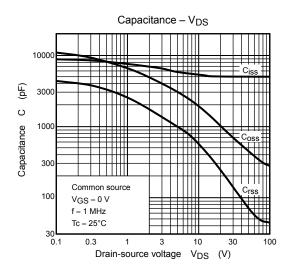


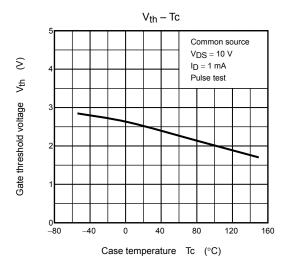


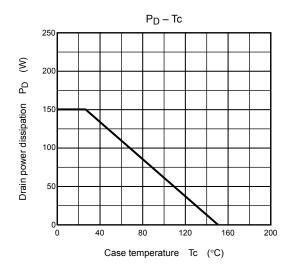
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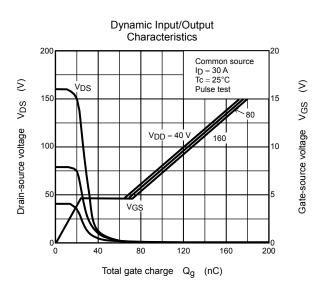


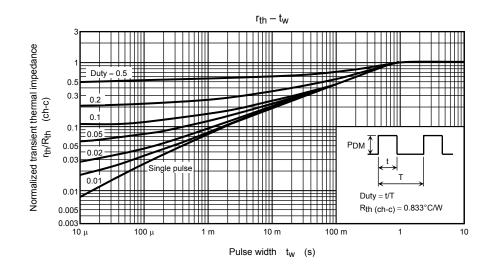


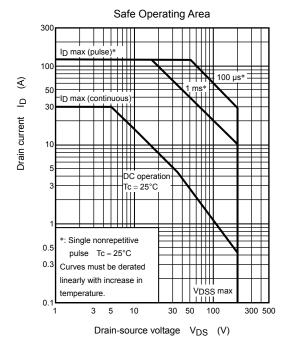


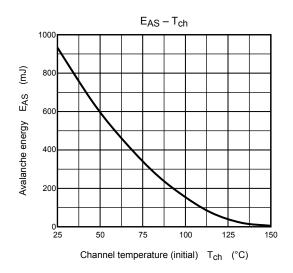


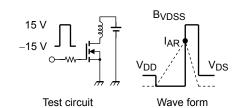












$$R_G$$
 = 25 Ω
 V_{DD} = 50 V, L = 1.66 mH

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$

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